



Temperature measurements of dynamically compressed materials

SEM conference

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D.H. Dolan

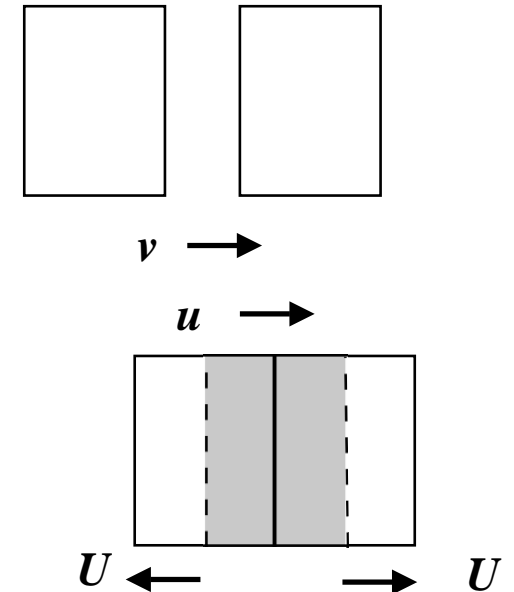
S. Becker and R. Hacking (BN)



Overview

- **Mechanical measurements**
 - Measure stress or velocity directly
 - Calculate other quantities (e.g., density) from conservation laws
- **Complete EOS requires temperature**
 - Helmholtz free energy: $F(T,v)$
 - Not explicit in conservation laws
 - Calculations very sensitive to response functions: c_v , k_t
 - Reveals underlying material physics
- **Temperature is hard to measure**
 - Fast rise times (1-100 ns)
 - Hostile environments

Impact experiment



Jump conditions

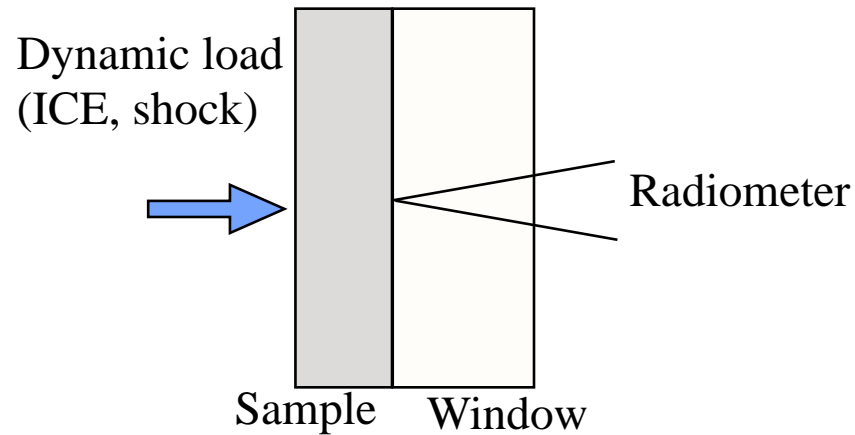
$$\frac{v}{v_0} = 1 - \frac{u}{U}$$

$$P - P_0 = \rho_0 U u$$

$$E - E_0 = \frac{1}{2}(P + P_0)(v_0 - v)$$

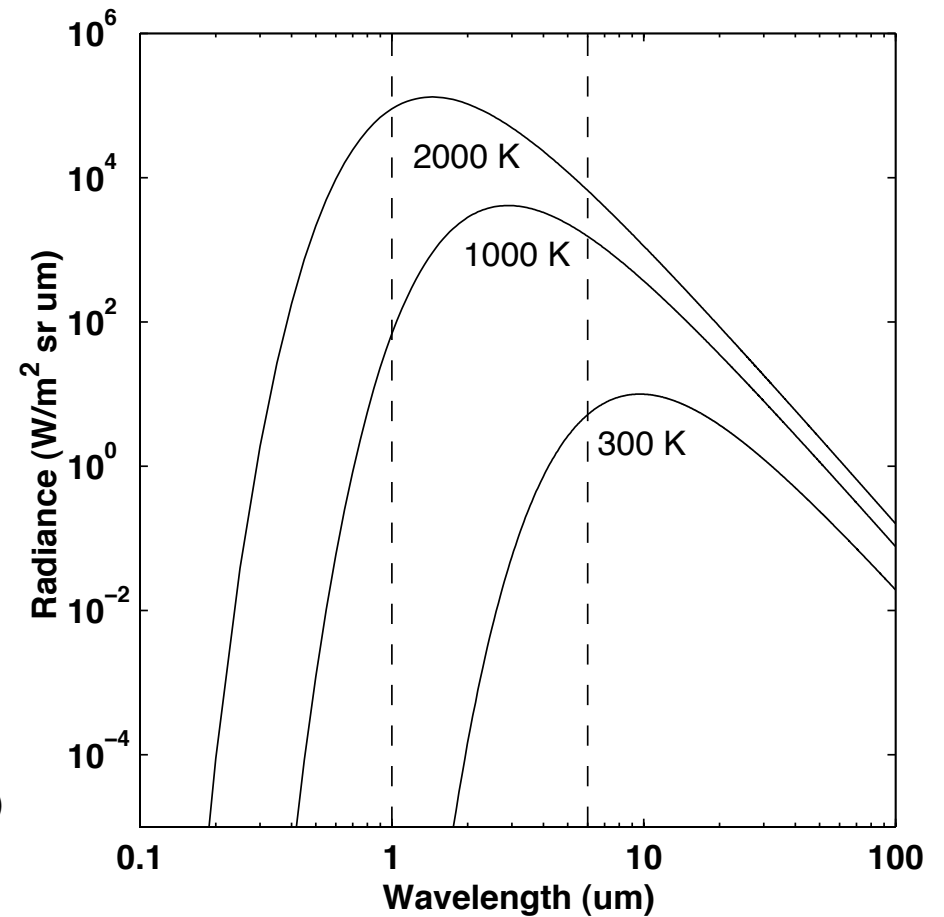


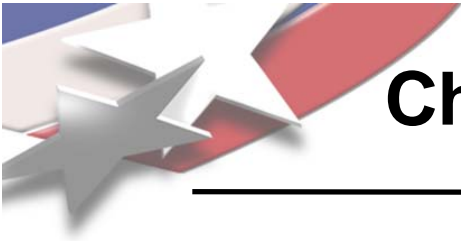
Pyrometry overview



Blackbody radiance (Power/area/solid angle)

$$L_{BB}(\lambda, T) = \frac{c_1}{\lambda^5 (e^{c_2/\lambda T} - 1)}$$





Challenge #1: Radiance measurements

- **Nanosecond radiance measurements are difficult**
 - Limited number of photons
 - Stray light mitigation issues
 - Single event experiments
- **Low temperatures (<1000 C) demand IR sensing**
 - Limited responsivity/bandwidth
 - Standard optical fiber doesn't work beyond 2000 nm
 - Chromatic aberrations



Challenge #2: Temperature calculation

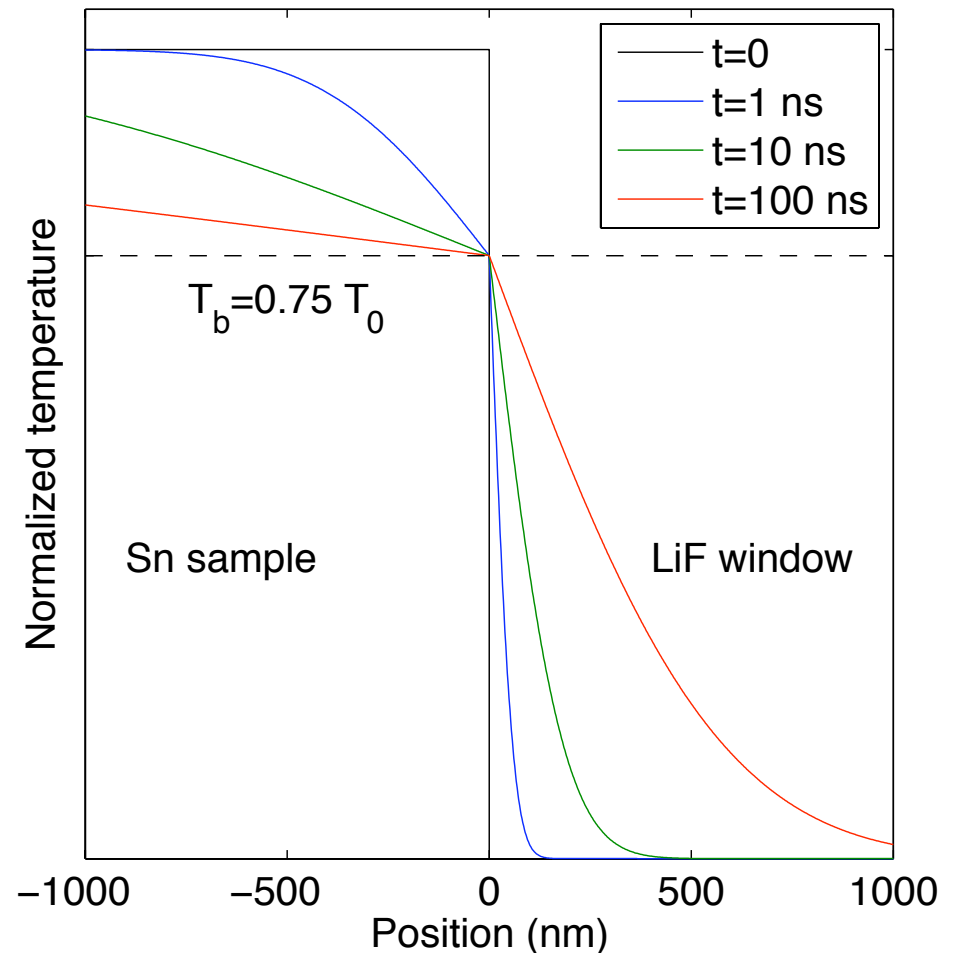
$$L(\lambda, T) = \varepsilon(\lambda, T) \frac{c_1}{\lambda^5 (e^{c_2/\lambda T} - 1)}$$

Underdetermined system!

- **Real materials are not blackbodies!**
 - Gray body assumption only useful for closely spaced, narrowband measurements
- **Emissivity= 1 - Reflectance - Transmittance**
 - $0 \leq \text{Emissivity} \leq 1$
 - Well characterized at ambient conditions
 - ~0.1 for metals (infrared)
- **How does emissivity change under dynamic compression?**
 - Material changes (temperature, pressure, phase)
 - Geometric changes (specular-diffuse)

Challenge #3: Interpretation

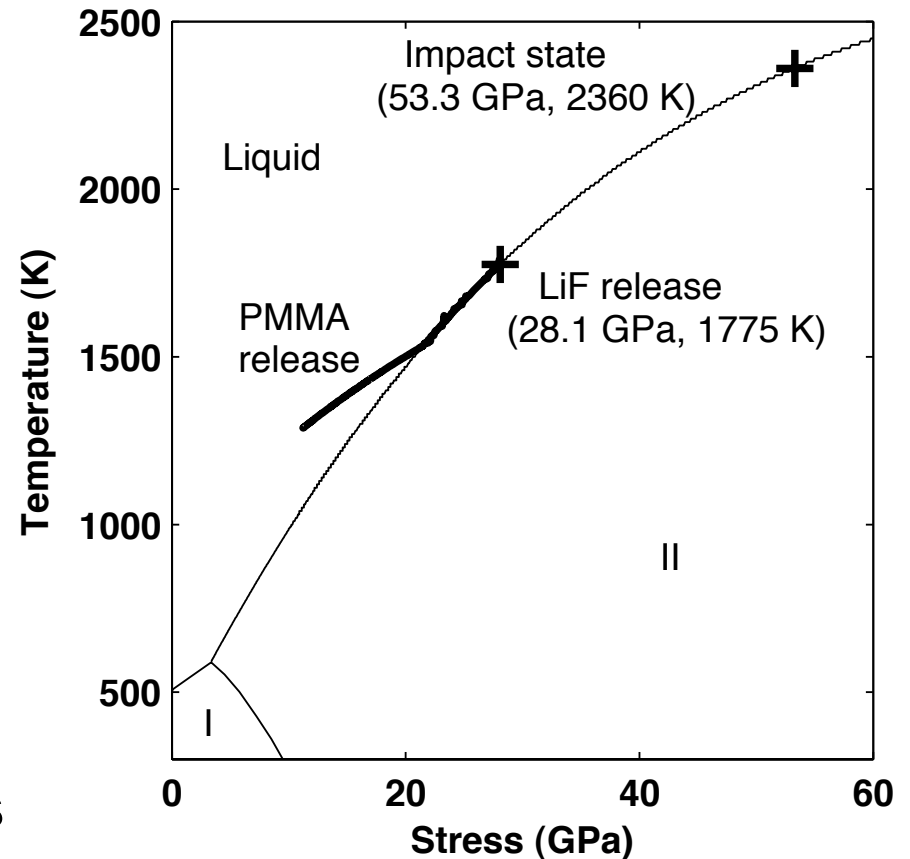
- What temperature is being measured?
 - Window changes loading
 - Cold window draws heat from warm sample
 - What about epoxy?
- Windowless experiments...
 - Zero stress state
 - Spallation issues

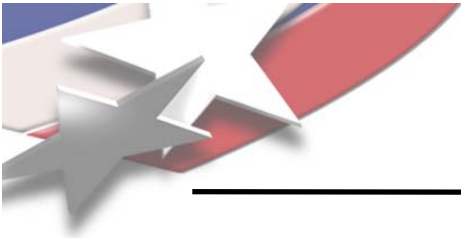


Challenge #4: Validation

- **How does one verify temperature?**
 - No mechanical analogue
- **Alternate diagnostics**
 - Microsensors
 - Neutron resonance spectroscopy (LANSCE)
- **Mixed phase measurements**
 - High pressure “ice/water bath”
 - Melt line data is ambiguous at high pressures

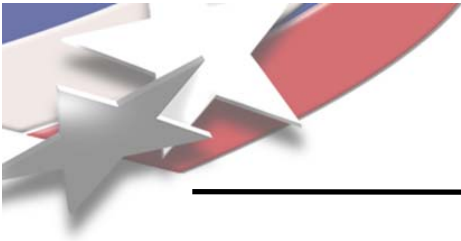
Conceptual mixed phase measurement (Sn)





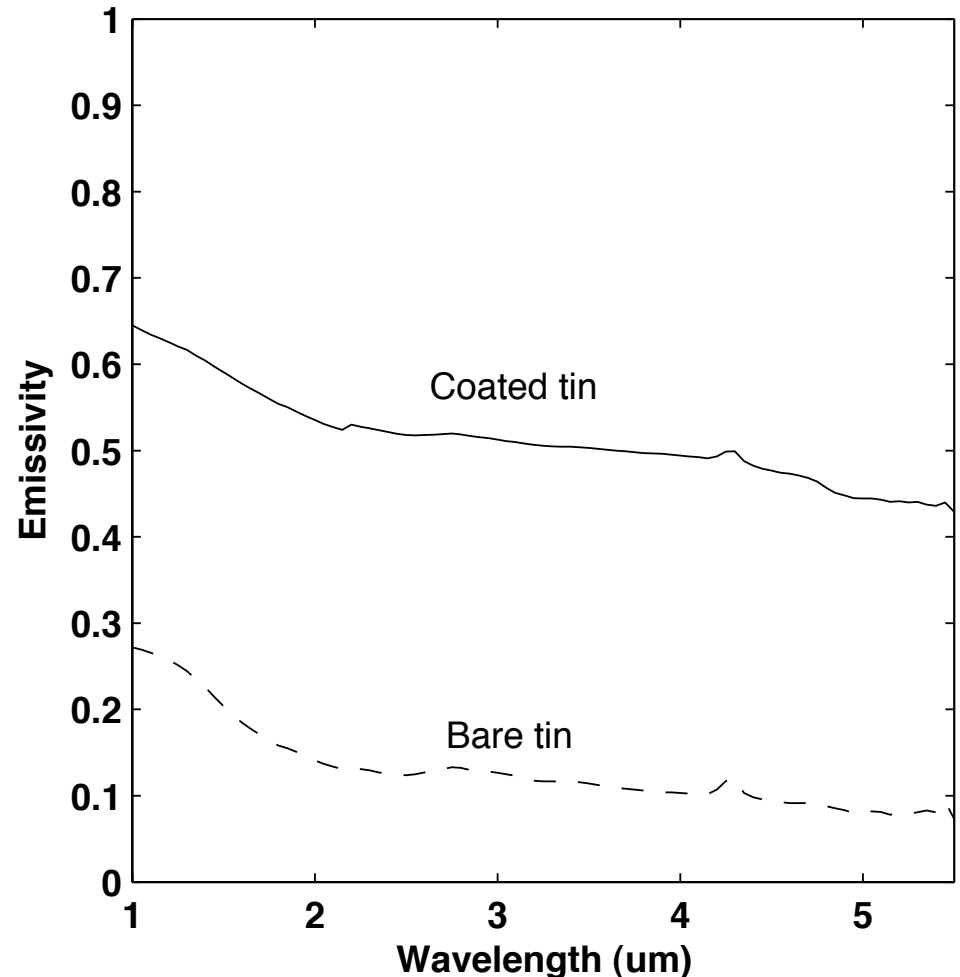
What can we do?

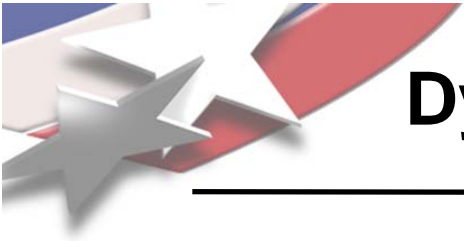
- Low temperatures demand IR pyrometry
 - Open beam relay
 - Mirror based to avoid chromatic aberrations
 - Only practical for short distances
 - New fiber materials: sapphire, fluoride
- Control the emissivity problem
 - High emissivity films
 - Dynamic emissivity characterization
 - Design probe to boost “effective emissivity”
- Design experiments to probe thermal conductivity
- Develop temperature standards
 - DAC melt line studies (resistive + laser heating)
 - Tailored samples?



High emissivity films

- **Wanted: opaque thin films ($<1\text{ }\mu\text{m}$) that are not reflective**
 - Match sample temperature
 - Mimic blackbody emission
- **Need to know (P,T) dependence**
 - Then you have an emissivity standard!



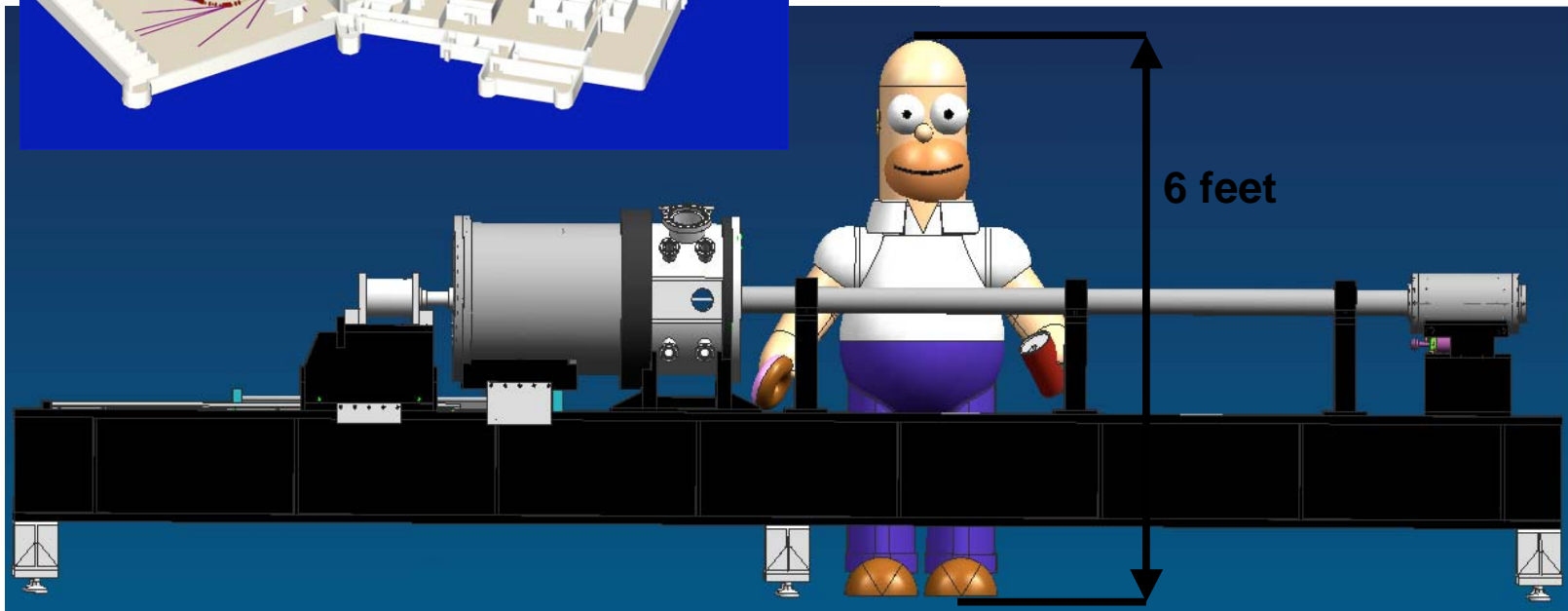
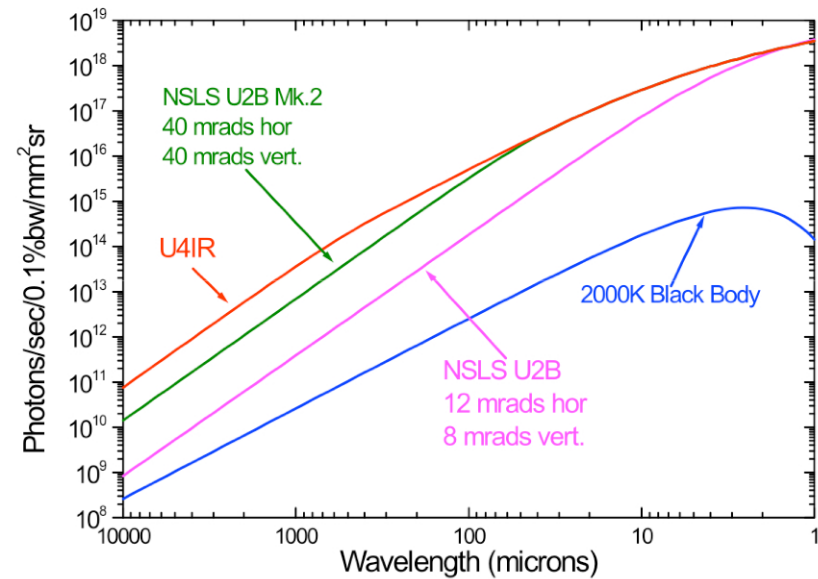
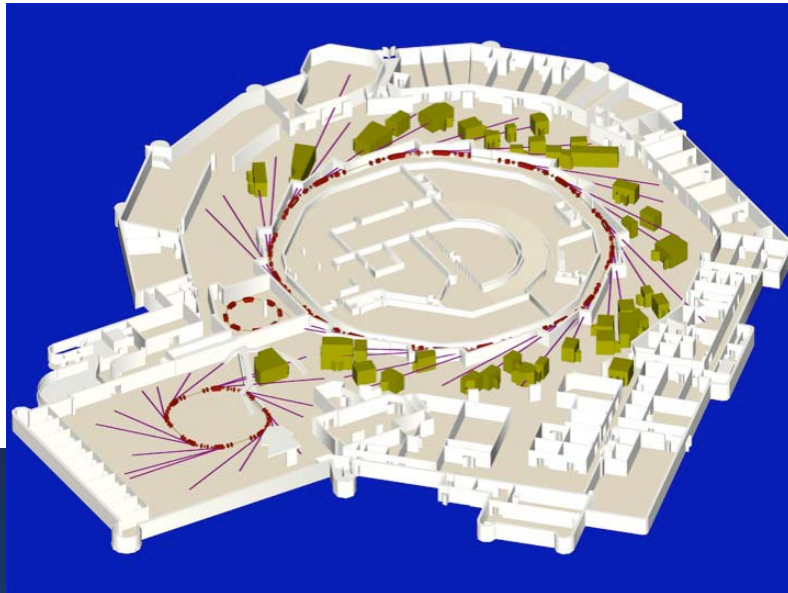


Dynamic emissivity characterization

- **Measure reflectance of opaque materials under shock compression**
 - Controlled temperature
 - Well defined stress
- **Bright, broadband light source required**
 - NSLS VUV ring (Brookhaven National Laboratory)
 - Simultaneously cover near- and mid-infrared
- **Many technical challenges**
 - Few (if any) real time synchrotron studies
 - New environment for impact experiments
 - Reflectance geometry (specular vs. diffuse)

NSLS impact system

National Synchrotron Light Source (BNL)





Summary

- **Temperature measurements are hard, but important**
- **Numerous challenges remain**
 - Practical issues
 - Emissivity problem
 - Interpretation (e.g., thermal conduction)
 - Validation
- **Dynamic broadband emissivity measurements are forthcoming**